Floating c-Si Thin Films for Solar Cells

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FFG CONCEPT

- Dissolve Si-source in molten In or Sn bath at T₂, where 800°C T₂ 1,000°C
- **Cool** molten bath to T_1 , where $T_1 \ll T_2$
- Due to lower solubility of Si at T₁ than at T₂, Si separates (or is driven) out of solution, and
- Due to lower density of Si than that of the molten bath, Si floats to the top surface of the molten metallic bath
- During cooling, Si grows as a floating Si-foil, along the direction of its thickness
- Growth at the Interface is free of interfacial stress (like space growth), producing extra large grains (or single crystalline) flat and smooth Si-foil essentially free of dislocations

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In-Si Phase Diagram

Indium-Silicon Binary Alloy Phase Diagram (based on 1990 Olesinski R.W.)



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Partial In-Si Phase Diagram

<u>Si wt% in In vs Temp (°C)</u>



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FFG RIBBON CONCEPT



Figure 1A



Figure 1B

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PROSPECTS

- Since growth of FFG Si-foil takes place across the entire foil/bath interface, in the direction of the foil thickness, foil production rate can be exceptionally high <u>10-50 m²/hr</u> (in a single line).
- The authors are not aware of any physical limitations on the width and length of FFG Si ribbons or panels.
- Si ribbons or panels with thickness between 50-100µm, width 1 meter, and length of several meters are anticipated in production
- Si material costs and energy savings are estimated at >80% compared with conventional sliced wafers.

FFG process is inherently self-purifying, enabling the use of lower grade Si source.

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Proof of Concept Goals

- Demonstrate growth of a continuous sheet of floating Si-foil from In and/or Sn melt solution
- Demonstrate continuous Si-foil on the frozen In and/or Sn melt
- Demonstrate separation of the Si-foil from the molten bath
- Criteria for success:
 - 1. verify that precipitated Si floats as a continuous Si-foil on top of molten In or Sn
 - 2. grain size 10µm

Proof of Concepts Goals (2)

- **3.** Separate Si-foil from In and/or Sn melt
- 4. Si-foil thickness 50-200µm
- 5. Si-foil purity: 1000 ppm In or Sn in Si-foil
- 6. Si-foil minority lifetime: 1.0 µsec, and/or
- 7. Carrier mobility: 10 cm⁻²V⁻¹s⁻¹

<u>Results</u>

Accomplished most of the goals:

- 1. Demonstrated continuous Si-foil on frozen In bath
- Demonstrated grain-size 1000µm (up to 7.4mm)
- **3.** Separated Si-foils using a quartz strainer
- 4. Demonstrated Si-foil thickness 50-200µm
- Si-foil purity: In impurities ~14ppb, other impurities < 0.1ppm, oxygen ~1.8ppm, carbon below detection limit (< 50ppb)
- 6. Mobility: Minority lifetime: > 10 µsec
- 7. Si-foil properties suitable for solar cell applications

Experimental Set-Up



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<u>Si-Source</u>



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<u>Quartz Strainer</u>



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Experiment #150



1,000°C; end of Si-source dissolution in In melt. Feb. 27, 2009.

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Crucible after Run #07



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Crucible after Run #07



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Scrapped Spot 1, Run #07



50µm

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Scrapped Spot 1, Run #07



Loc A; 200X

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Top View of Crucible Run #120



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Flat crystal: ~7.4mm long; area ~ 0.18cm²; ~75µm thick; grid lines 0.25" apart.

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LA-ICPMS Elemental Analysis #123

	Concentration		Concentration
Element	(ppm wt)	Element	(ppm wt)
Li	< 0.1	ln	* Interference
Be	< 0.1	Sn	< 0.1
В	< 0.1	Sb	< 0.1
Na	< 1	Те	< 0.1
Mg	< 0.1	Cs	< 0.1
AI	< 0.1	Ba	< 0.1
Si	Matrix	La	< 0.1
Р	< 10	Ce	< 0.1
к	< 1	Pr	< 0.1
Ca	< 1	Nd	< 0.1
Sc	< 0.1	Sm	< 0.1
Ti	< 0.1	Eu	< 0.1
v	< 0.1	Gd	< 0.1
Cr	< 0.1	Tb	< 0.1
Mn	< 0.1	Dy	< 0.1
Fe	< 1	Но	< 0.1
Co	< 0.1	Er	< 0.1
Ni	< 0.1	Tm	< 0.1
Cu	< 0.1	Yb	< 0.1
Zn	< 0.1	Lu	< 0.1
Ga	< 0.1	Hf	< 0.1
Ge	< 0.1	Та	< 0.1
As	< 0.1	W	< 0.1
Se	< 0.1	Re	< 0.1
Rb	< 0.1	Os	< 0.1
Sr	< 0.1	lr	< 0.1
Y	< 0.1	Pt	< 0.1
Zr	< 0.1	Au	< 0.1
Nb	< 0.1	Hg	< 0.1
Мо	< 0.1	TI	< 0.1
Ru	< 0.1	Pb	< 0.1
Rh	< 0.1	Bi	< 0.1
Pd	< 0.1	Th	< 0.1
Ag	< 0.1	U	< 0.1
Cd	< 0.1		

Table 1. Trace elemental concentrations found in silicon sample #123 RTL-123.

* Unable to determine value due to contamination from previous testing.

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Sample #150 Top Surface



Flat bicrystal: ~7.0mm long; area ~ 0.26cm²; ~96µm thick.

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Sample #150 Bottom Surface



Flat bicrystal: ~7.0mm long; area ~ 0.26cm²; ~96µm thick.

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Sample #152 Top Surface



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Sample #152 Bottom Surface



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#152 Smooth Bottom Surface



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<u>Summary</u>

- Continuous floating Si-foils on In melt, of ~30mm diameter size, were demonstrated. Foil thickness was about 50-200µm.
- Flat Si crystals > 7mm size were obtained.
- EDX and LA-ICPMS analyses indicate very high purity Si material, with most metals Impurity level below 0.1ppm.
- SIMS analysis indicates In impurity level as low as 14 ppb! Oxygen ~1.8ppm; C < 50ppb.</p>
- > Measured minority lifetime > 10 µsec.
- The demonstrated Si quality and purity meet requirements for solar cell applications.

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